Assembly & Test Benchmarking Study





Why Engage in an A&T Benchmarking Study?

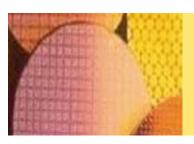
- Cost structure shifts to back-end
- Missing a centrally organized benchmark entity
- Strong interest from multiple ASAT suppliers and IDM companies knowledge sharing
- Turn knowledge into driving actions
- Significant potential for efficiency and cost improvements
- Proven track record from FOA best benchmarking administrator

Performance efficiency Examples

Area	Typical Level	Benchmark
Full Lot Size	75%	90%
Changeover Frequency	>70%	
First Pass Yields	95%	98%
X-Factor	>4X	2X
Staffing Levels	120%	100%
Bottleneck OEE	55% - 65%	>90%
M-Ratio	<1:1	9:1
Availability – Mean / CV	<88% / >30%	>93% / 10%

From MAX Engagements





Proven Success (Front-End)

Fab Owners Association

- 26 IDM Companies
- 100mm 200mm Fabs
- 40 participating Fabs

Survey #3

- Most detailed benchmark survey covering Fab performance
- 253 indices and metrics
- Automated analysis tool developed by MAX
- Robust validation process

Survey #3 2014 Fabs at Glance





0.9M Wafers / Qtr 20M Aligns / Qtr **9,000**

4,000 Operators

1,300 Technicians **700** Engineers





Objectives

Provide the most extensive and complete operational benchmarking analysis to participating companies

Study Quality

- Drive Data Accuracy
- Standardize QuestionsDefinition and Scope
- Evaluate Year on YearData

- Provide Actionable
 Information
- Incorporate ParticipantsFeedback



Participants (Signed On)

IDM

10 Companies

15 Sites

OSAT

4 Companies

10 Sites





Typical Survey Process

Phase 1 - Preparation

- Final Participants List Closure
- NDA & Benchmarking Agreement Signoff
- Study Questionnaire Review & Participants feedback
- Agree on Data Capture Period
- Questionnaire Revision

2 months

Phase 2 - Data Collection

- Study Questionnaire Distribution
- Kick-off Conference Calls with Each Site
- Data Collection By Site

2 months

Phase 3 – Data Validation

- First Data Review
- Second Data Review
- Third Data Review
- Data Review by Participating Sites

1 months

Phase 4 – Data Analysis

- Data Analysis
- Data Analysis tool Distribution (MS Excel w Macros)
- Final Report Distribution





Data Validation Process

Individual Site Check

-Historical Data

-Theoretical Indicators

Intra-Group Analysis

-Outliers

-Correlations

Survey Wide Analysis

-Statistical Analysis

-Ratio Analysis

Participant Check

-Participant Feedback

-Data Verification





Benchmarking Scope

Area	Operation Group	Operation Type
FOL	BACKGRIND	BACK_GRIND_INCOMING_INSP
FOL	BACKGRIND	BACK_GRIND
FOL	BACKGRIND	BACK_GRIND_THICK_MEAS
FOL	BACKGRIND	BACK_GRIND_FINAL_INSP

Area	Operation Group	Operation Type
FOL	SAW	WAFER_MOUNT
FOL	SAW	WAFER_SAW
FOL	SAW	WAFER_MOUNT_CURE
FOL	2ND OPTICAL INSP	2ND_OPTICAL_INSP
FOL	2ND OPTICAL INSP	2ND_OPTICAL_GATE
FOL	2ND OPTICAL INSP	2ND_OPTICAL_INKCURE
FOL	DIE ATTACH	DIE_ATTACH
FOL	DIE ATTACH	POST_DA_CURE
FOL	WIREBOND	WIREBOND
FOL	3RD OPTICAL INSP	3RD_OPTICAL_INSP_SAMP
FOL	3RD OPTICAL INSP	3RD_OPTICAL_GATE
FOL	CLEAN	PLASMA_CLEAN
EOL	MOLD	MOLD
EOL	MOLD	POST_MOLD_CURE
EOL	MARKING	BOTTOM_LASER_MARK
EOL	MARKING	TOP_LASER_MARK
EOL	MARKING	LASER_MARK
EOL	TRIM AND SINGULA	TRIM_SIN_AUTO
EOL	TRIM AND SINGULA	TRIM_SIN_AUTO
EOL	4TH OPTICAL INSP	4TH_OPTICAL_INSP_SAMP
EOL	4TH OPTICAL INSP	4TH_OPTICAL_GATE

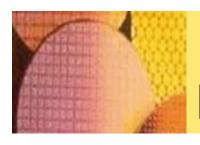
Area	Operation Group	Operation Type
PROBE	PROBING	PROBE_INCOMING_INSP
PROBE	PROBING	PROBE_PROBING
PROBE	PROBING	PROBE_OPTICAL_INSP
PROBE	PROBING	PROBE_INKING
PROBE	PROBING	PROBE_OPTICAL_INSP

Area	Operation Group	Operation Type
PRE_TEST	REFLOW	REFLOW
PRE_TEST	TEMP CYCLE	TEMP_CYCLE
PRE_TEST	OPEN SHORT	OPEN_SHORT_1
PRE_TEST	OPEN SHORT	OPEN_SHORT_1
PRE_TEST	BURN IN	BURN_IN
PRE_TEST	OPEN SHORT	OPEN_SHORT_2
PRE_TEST	OPEN SHORT	OPEN_SHORT_2
PRE_TEST	TEMP CYCLE	TEMP_CYCLE2
PRE_TEST	X-RAY	X_RAY
PRE_TEST	MVI	MVI

Area	Operation Group	Operation Type
TEST	TEST	TEST_PASSES
TEST	TEST	CI
TEST	TEST	CI

Area	Operation Group	Operation Type
BACK END	BACKEND	LEADFORM
BACK END	BACKEND	TAPE_AND_REEL
BACK END	BACKEND	FINAL_INSPECTION

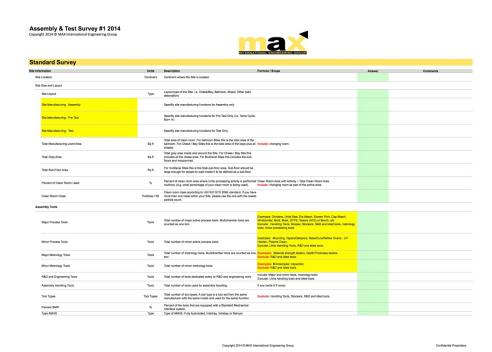




Benchmarking Questionnaire

Sections:

- Site Information
- Production
- Facility Area
- Cycle Time
- Technology
- Staffing
- Yield & Quality
- Cost
- Maintenance

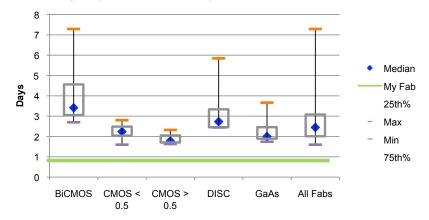




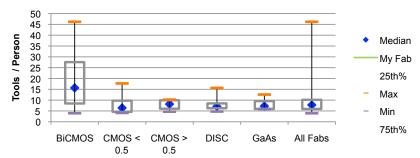


Analyses Sample

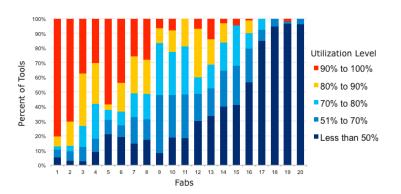
Average Cycle time Per Layer



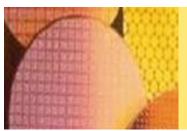
Tools per Operator



Tools by Utilization Level







Timeline Proposal

Time Line	1 st Qtr	2 nd Qtr	3 rd Qtr
Questionnaire Definition			
Questionnaire Distribution			
Data Submission			
Data Analysis			
Survey Results			





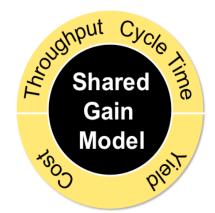
Who we are

Transforming Semiconductor, Solar and LED factories' performance





140 Programs





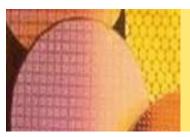
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Return on our fee

CAPEX Avoidance Personnel Productivity Yield Improvement Cost Savings

Lineage

Established in NJ, USA		First 300mm Factory	First M&A	Site Mgmt	
1999	2003	2007		2011	2013
	First EU Project	Shared Gain Model	Multi- Proje		Global IE Mgmt



Lean Six-Sigma Foundation

MAX Black Ops™ - The Villanova University Lean Six Sigma Program

5 Master Black Belts

35
Black Belts

45
Green Belts

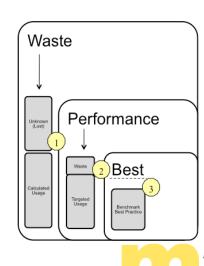
Program - ASQ Certified

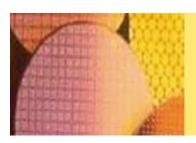
Tailored for Semiconductors/LED Industry

Lean principles as a way of life

Find reduce and eliminate waste

- Quantify loses comparing cost to bottom up calc.
 - Investigate where significant
- Look for performance improvement in equipment or process.
- Compare revised performance to benchmark where possible





MAX - The Benchmarking Authority in Semiconductors

Associations



Benchmark Admin Associate Member of the Year - 2009





Papers and Presentations

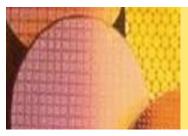




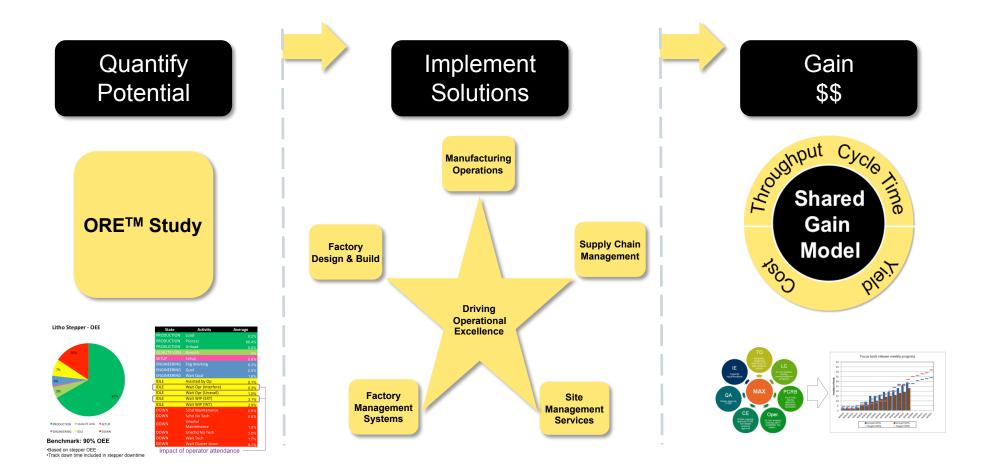








Client Experience







THANK YOU

To Participate Contact:

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